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Certificate of Transmission under 37 CFR 1.8 I hereby certify that this correspondence is being facsimile transmitted to the United States Patent and Trademark Office 08/17/2004 ÖП Date Sheryl Lee Typed or printed name of person signing Certificate Note: Each paper must have its own certificate of transmission, or this certificate must identify each submitted paper. APPLICATION NUMBER: 10/605,377 PAPERS INCLUDED: (1) Transmittal Form 1 PAGE (2) Fee Transmittal 1 PAGE (3) Information Disclosure Statement 29 PAGES

This collection of information is required by 37 CFR 1.8. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 1.8 minutes to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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TRANSMITTAL FORM (to be used for all correspondence after initial Total Number of Pages in This Submission	Application Number First Named Inventor	Approved for use through 07/31/2008. QMB 0651-0031 Patent and Tredemark Office; U.S. DEPARTMENT OF COMMERCE Rection of Information unless it displays a valid QMB control number. 10/605,377 09/25/2003 Jun-Cheng Lai 1752 LKSP0022USA
	ENCLOSURES (Check all	that apply)
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This collection of information is required by 37 CFR 1.5. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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FROM: Winston Hsu, PATENT AGENT, REG. NO.: 41,526

SERIAL NO.: 10/605,377

ATTORNEY DOCKET NO.: LKSP0022USA

SUBJECT: INFORMATION DISCLOSURE STATEMENT

TOTAL PAGES: 33 PAGES (INCLUDING COVER PAGE)

Winston Hsu 2004/08/17

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AUG 1 7 2004

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Jun-Cheng Lai

Filing Date: 09/25/2003

Serial No.: 10/605,377

Art Unit: 1752

Docket No.: LKSP0022USA

Title: METHOD OF IMPROVING A RESOLUTION OF CONTACT

HOLE PATTERNS BY UTILIZING ALTERNATE PHASE

10 SHIFT PRINCIPLE

To: Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

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Subject: Information disclosure statement Under 37C.F.R.§1.56 and 37C.F.R.§1.97(b).

Dear Sir:

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This is an Information Disclosure Statement in accordance with the duty to disclose information material to patentability under 37 C.F.R. \$1.56. Applicants wish to make of record the document listed on the accompanying form PTO/SB/08. It is respectfully requested that the Examiner initials the cited reference on the form and that it be made of record in the application and that a copy of the initialed form be sent to Applicants with the next communication from the Examiner.

Since the information disclosure statement is filed

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before the mailing of a first Office action on the merits, the requirement set forth in 37 C.F.R.\$1.97(b)(3) is satisfied. The prior art patent contained in the information disclosure statement was cited in communications from the Taiwan Intellectual Property Office on 06/08/2004. Applicant sincerely hopes that the examiner can consider the item contained in the information disclosure statement.

According to the requirement set forth in 37 C.F.R.\$1.98 and M.P.E.P. 609, the applicant is submitting copies of the reference cited by the Taiwan Intellectual Property Office (Taiwan Patent No. 423048, published Feb. 21, 2001) and a concise explanation of the relevance in this application hereinafter.

Taiwan Patent No. 423048 discloses forming a plurality of interconnection patterns 50 having good resolution by utilize an alternating phase shift mask (Please refer to Fig.1 and Fig.2). On the alternating phase shift mask, light permeable regions 20 and light permeable regions 30, having a thickness different from a thickness of the light permeable regions 20, are surrounded by an opaque region. The opaque region comprises interconnection line patterns in the shape of a line and a peripheral protection region. Due to the difference between the thickness of the light permeable regions 20 and 30, light passing through the light permeable regions 20 has a phase shift of 180 degrees relative to light passing through the light permeable regions 30. Under the circumstances, diffraction lights are cancelled out from each other

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at the edge of the interconnection patterns 50 to improve a resolution between the adjacent interconnection patterns 50.

- Independent claims 1 and 9 of the present application are repeated here for reference:
 - 1. A lithography method for forming a plurality of closed patterns in a photoresist layer on a substrate, the patterns being isolated from each other and being arranged in an array, the lithography method comprising:

providing a phase shift mask (PSM), wherein the phase shift mask comprises:

- a plurality of first phase shift transparent regions;
 - a plurality of second phase shift transparent regions having a phase shift relative to the first phase shift transparent regions; and
- a non-phase shift region, wherein the first

 phase shift transparent regions and the second

 phase shift transparent regions are regularly

 interlaced in an array, and each of the first phase

 shift transparent regions and each of the second

 phase shift transparent regions are separated by

 the non-phase shift region; and

performing an exposure process to form the closed patterns in the photoresist layer, wherein the closed patterns are corresponding to the first phase shift transparent regions and the second phase shift transparent regions.

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9. A lithography method for forming a plurality of closed patterns in a photoresist layer on a substrate, the patterns being isolated from each other and being arranged in an array, the lithography method comprising:

providing a phase shift mask (PSM), wherein the phase shift mask comprises:

- a plurality of first phase shift transparent regions;
- a plurality of second phase shift transparent regions having a phase shift relative to the first phase shift transparent regions; and
 - a non-phase shift region, wherein portions of the first phase shift transparent regions and portions of the second phase shift transparent regions are regularly interlaced in an array, and each of the first phase shift transparent regions and each of the second phase shift transparent regions are separated by the non-phase shift region; and

performing an exposure process to form the closed patterns in the photoresist layer, wherein the closed patterns are corresponding to the first phase shift transparent regions and the second phase shift transparent regions.

Compared with Taiwan Patent No. 423048, the present application method of forming the closed patterns in the photoresist layer is to utilize a phase shift mask having the first phase shift transparent regions and the second phase shift transparent regions regularly interlaced in an array. Because the first phase shift

transparent regions and the second phase shift transparent regions are regularly interlaced in an array, diffraction lights are cancelled out from each other along two dimensions to form the closed patterns.

- 5 In Taiwan Patent No. 423048, the light permeable regions 20 and the light permeable regions 30 are regularly interlaced along one dimension. Therefore, the diffraction lights, canceling out from each other at the edge of the interconnection patterns 50, are 10 only along one dimension. In other words, it is impossible to form closed patterns having a good resolution according to the method disclosed by Taiwan Patent No. 423048.
- In summary, the method disclosed by the present application is able to form closed patterns. The method disclosed by Taiwan Patent No. 423048 can only form interconnection line patterns rather than the closed patterns, such as contact hole patterns and a logic cell patterns of a logic circuit.

Since claims 1 and 9 of the present application are substantially different from the prior art patent Taiwan Patent No. 423048, and all other claims are dependent on claims 1 and 9, a quick allowance of the present application is sincerely requested.

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Respectfully Submitted,

5 Wundon Hour

Date:

8/10/2009

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10 U.S.A.

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PTO/SB/08A (08-03)
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_		First Named Inventor	Jun-Cheng Lai	
STATEMENT BY APPLICANT	Art Unit	1752		
(Use a	(Use as many sheets as necessary) Examiner Name			
et 1	of 1	Attorney Docket Number	LKSP0022USA	

Examiner Gite Initials* No.1	Cite No. ¹	Number-Kind Code ^{2 (f known)}	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
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Examiner
Signature

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not

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